

FDD6692/FDU6692

30V N-Channel PowerTrench® MOSFET

General Description

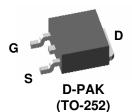
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low RDS(ON) and fast switching speed.

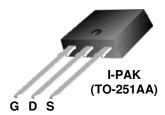
Applications

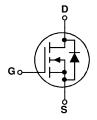
- DC/DC converter
- Motor drives

Features

- 54 A, 30 V. $R_{DS(ON)} = 12 \ m\Omega \ @V_{GS} = 10 \ V$ $R_{DS(ON)} = 14.5 \ m\Omega \ @V_{GS} = 4.5 \ V$
- Low gate charge (18 nC typical)
- · Fast switching
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS}(\mbox{\scriptsize ON})}$







Absolute Maximum Ratings TA=25°C unless otherwise noted

| Symbol | Parameter | | Ratings | Units |
|-----------------------------------|----------------------------------------|------------|-------------|-------|
| V _{DSS} | Drain-Source Voltage | | 30 | V |
| V _{GSS} | Gate-Source Voltage | | ±16 | V |
| I _D | Drain Current - Continuous | (Note 3) | 54 | Α |
| | - Pulsed | (Note 1a) | 162 | |
| P _D | Power Dissipation for Single Operation | (Note 1) | 57 | W |
| | | (Note 1a) | 3.8 | |
| | | (Note 1b) | 1.6 | |
| T _J , T _{STG} | Operating and Storage Junction Tempera | ture Range | -55 to +175 | °C |

Thermal Characteristics

| R _{θJC} | Thermal Resistance, Junction-to-Case | (Note 1) | 2.6 | °C/W |
|------------------|-----------------------------------------|-----------|-----|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient | (Note 1a) | 40 | °C/W |
| R _{eJA} | Thermal Resistance, Junction-to-Ambient | (Note 1b) | 96 | °C/W |

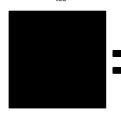
Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape width | Quantity |
|----------------|---------|----------------|-----------|------------|------------|
| FDD6692 | FDD6692 | D-PAK (TO-252) | 13" | 12mm | 2500 units |
| FDU6692 | FDU6692 | I-PAK (TO-251) | Tube | N/A | 75 |

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|----------------------------------------|---------------------------------------------------|-----------------------------------------------------------------------------------------------------------|-----|-------------|------------|-------|
| Drain-Sc | ource Avalanche Ratings (Note | 2) | | l | l | |
| W _{DSS} | Drain-Source Avalanche Energy | Single Pulse, V _{DD} = 15 V, I _D =14A | | | 165 | mJ |
| I _{AR} | Drain-Source Avalanche Current | | | | 14 | Α |
| Off Char | acteristics | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$ | 30 | | | V |
| ΔBV _{DSS} ΔT _J | Breakdown Voltage Temperature Coefficient | I_D = 250 μ A, Referenced to 25°C | | 26 | | mV/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$ | | | 1 | μΑ |
| I _{GSSF} | Gate-Body Leakage, Forward | $V_{GS} = 16 \text{ V}, \qquad V_{DS} = 0 \text{ V}$ | | | 100 | nA |
| I_{GSSR} | Gate-Body Leakage, Reverse | $V_{GS} = -16 \text{ V}, V_{DS} = 0 \text{ V}$ | | | -100 | nA |
| On Char | racteristics (Note 2) | | | | | |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$ | 1 | 1.6 | 3 | V |
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate Threshold Voltage Temperature Coefficient | I_D = 250 μ A, Referenced to 25°C | | - 5 | | mV/°C |
| $R_{DS(on)}$ | Static Drain–Source On–Resistance | $ \begin{aligned} V_{GS} &= 10 \ V, & I_D &= 14 \ A \\ V_{GS} &= 4.5 \ V, & I_D &= 13 \ A \end{aligned} $ | | 9.5 11.5 | 12 14.5 | mΩ |
| | | $V_{GS} = 10 \text{ V}, I_D = 14 \text{ A}, T_J = 125^{\circ}\text{C}$ | | 16.5 | 18 | _ |
| I _{D(on)} | On–State Drain Current | $V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$ | 50 | | | A |
| g FS | Forward Transconductance | $V_{DS} = 5 \text{ V}, \qquad I_{D} = 14 \text{ A}$ | | 54 | | S |
| | Characteristics | 1 | 1 | 1 | ı | ı |
| C _{iss} | Input Capacitance | $V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$ | | 2164 | | pF |
| Coss | Output Capacitance | f = 1.0 MHz | | 357 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 138 | | pF |
| Switchir | g Characteristics (Note 2) | | | | | |
| $t_{d(on)}$ | Turn-On Delay Time | $V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$ | | 9 | 18 | ns |
| t _r | Turn-On Rise Time | $V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$ | | 5 | 10 | ns |
| $t_{\text{d(off)}}$ | Turn-Off Delay Time | | | 35 | 56 | ns |
| t _f | Turn-Off Fall Time | | | 10 | 20 | ns |
| Q_g | Total Gate Charge | $V_{DS} = 15 \text{ V}, \qquad I_{D} = 14 \text{ A},$ | | 18 | 25 | nC |
| Q _{gs} | Gate-Source Charge | $V_{GS} = 5 \text{ V}$ | | 5 | | nC |
| Q _{gd} | Gate-Drain Charge | | | 5 | | nC |
| Drain-S | ource Diode Characteristics | and Maximum Ratings | | | | |
| Is | Maximum Continuous Drain-Source | e Diode Forward Current | | | 3.2 | Α |
| V _{SD} | Drain-Source Diode Forward Voltage | $V_{GS} = 0 \ V, I_S = 3.2 \ A \qquad \text{(Note 2)}$ | | 0.72 | 1.2 | V |

Notes:

 R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.



a) $R_{\theta,JA} = 40$ °C/W when mounted on a 1in^2 pad of 2 oz copper



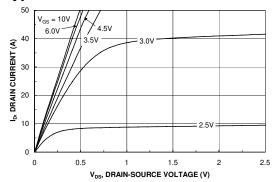
b) $R_{\theta JA} = 96^{\circ}C/W$ when mounted on a minimum pad.

Scale 1:1 on letter size paper

- 2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%
- 3. Maximum current is calculated as: $\sqrt{\frac{P_D}{R_{DS(ON)}}}$

where P_D is maximum power dissipation at $T_C = 25^{\circ}C$ and $R_{DS(on)}$ is at $T_{J(max)}$ and $V_{GS} = 10V$. Package current limitation is 21A

Typical Characteristics



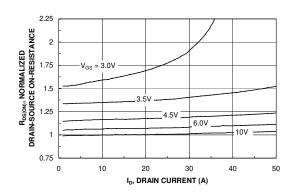
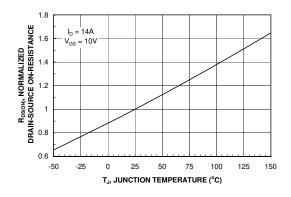


Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



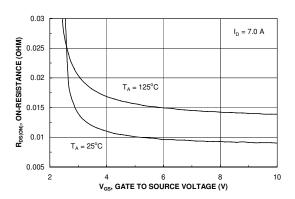
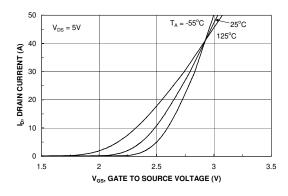


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



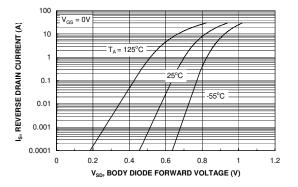
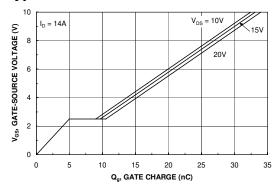


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



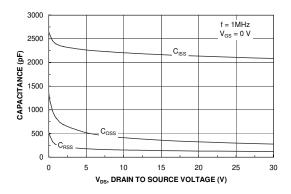
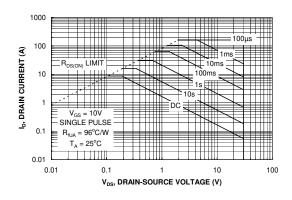


Figure 7. Gate Charge Characteristics.





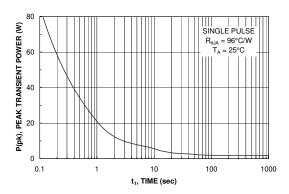


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

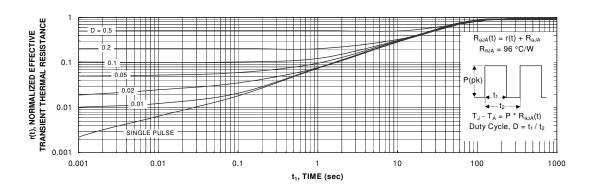


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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